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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT BY APPLICANT


Sheet 1 of 1

COMPLETE IF KNOWN

Application Number	10/650,282
Filing Date	August 28, 2003
First Named Inventor	Tianniu CHEN
Art Unit	1621
Examiner Name	Samuel A. Barts
Attorney Docket Number	2771-515-CIP

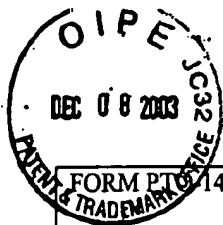
U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number	Publication Date MM-DD-YYYY	Issue Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
5/14		US-6,858,697	02-22-2005	02-22-2005	Mayorga et al.
		US-			
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Examiner signature		Date Considered	11/1/05
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*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

¹ All the foreign patents and publications that are not written in English language are accompanied by their respective English abstracts, which constitute concise explanation of relevance of the non-English patents and publications that satisfy the requirements of 37 C.F.R. §1.98(a)(3)(i), according to MPEP 609 III A(3).



FORM PT 1449 US Dept. of Commerce Patent and Trademark Office INFORMATION DISCLOSURE STATEMENT (use several sheets if necessary)	ATTORNEY DOCKET NO.	SERIAL NO.
	ATMI-515-CIP	10/650,282
	APPLICANT Tianniu Chen, et al.	
	FILING DATE August 28, 2003	GROUP TBA

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SA	AA	5,204,134	4/20/1993	Kirlin, et al.			
	AB	5,536,323	7/16/1996	Kirlin, et al.			
	AC	5,711,816	1/27/1998	Kirlin, et al.			
	AD	6,171,945	1/9/2002	Mandal, et al.			
	AE	4,745,169	5/17/1988	Sugiyama, et al.			
	AF	4,755,370	7/5/1988	Kray, et al.			
	AG	6,114,500	9/5/2000	Mori, et al.			
	AH	5,043,789	8/27/1991	Linde, et al.			
	AI	4,871,616	10/3/1989	Kimura, et al.			
	AJ	5,484,867	1/16/1996	Lichtenhan, et al.			
	AK	4,670,299	6/2/1987	Fukuyama, et al.			
	AL	5,047,492	9/10/1991	Weidner, et al.			
	AM	5,210,250	5/11/1993	Watanuki, et al.			
	AN	4,374,110	2/15/1983	Darnell, et al.			
	AO	4,156,689	5/29/1979	Ashby, et al.			
	SA	AP	5,804,040	9/8/1998			Asai, et al.

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		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLAS S	TRANSLATION YES	NO
							X (abstract only)	
SR	AQ	JP 50-111198	1/28/1974	Japan			X	

OTHER DOCUMENTS (Including Author, Title, Journal-Date, Page Number, Etc.)

SA	AR	Mantz, et al., "Thermolysis of Polyhedral Oligomeric Silsesquioxane (POSS) Macromers and POSS-Siloxane Copolymers", Chem. Mater., 1996, 8, pg. 1250-1259.
SA	AS	Ravi K. Laxman, Neil Hendrix Barry Arkles, Terry A. Tabler "Synthesizing Low-K CVD Materials for Fab Use" Semiconductor International, 11/1/2000

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EXAMINER 	DATE CONSIDERED 11/7/03
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	APPLICANT Tianniu Chen, et al.		
	FILING DATE August 28, 2003	GROUP TBA	

OTHER DOCUMENTS (Including Author, Title, Journal-Date, Page Number, Etc.)

5h	AT	Alfred Grill, et al., "Novel Low-k Dual-Phase Materials Prepared by PECVD, Mat. Res. Soc. Symp. Proc. Vol. 612, 2000 Materials Research Society
5h	AU	Albert Wang, et al. "TMCTS for Gate Dielectric in Thin Film Transistors", Mat. Res. Soc. Meeting 1996
5h	AV	A. Grill, et al., "Ultralow-k Dielectrics Prepared by Plasma-enhanced Chemical Vapor Deposition", Applied Physics Letters, Vol. 79, No. 6, Aug. 6, 2001.

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EXAMINER <i>StB</i>	DATE CONSIDERED 11/7/03
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INFORMATION DISCLOSURE STATEMENT (use several sheets if necessary)				APPLICANT Tianniu Chen			
				FILING DATE August 28, 2003		GROUP TBA	
U.S. PATENT DOCUMENTS							
EXAMINER TRADEMARK		PATENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
3/3		BA	10/015,326	Chongying Xu, et al.	X		12/31/2001
3/3		BB	10/301,109	Alexander S. Borovik	X		11/21/2002
FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER		PUBLICATION DATE	COUNTRY	CLASS	SUBCLAS S	TRANSLATION YES NO	
						X (abstract only)	
OTHER DOCUMENTS (Including Author, Title, Journal-Date, Page Number, Etc.)							
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EXAMINER 3/3					DATE CONSIDERED 11/7/05		
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INFORMATION DISCLOSURE STATEMENT (use several sheets if necessary)		APPLICANT Tianniu Chen, et al.					
		FILING DATE August 28, 2003		GROUP 1621			
U.S. PATENT DOCUMENTS							
	PATENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
3/B	AA 2004/054114A	3/18/2004	Mayorga, et al.	X			
	AB 4,087,448	05/1978	Rossmey, et al.				
	AC 4,127,598	11/1978	McEntee				
	AD 4,764,631	8/1988	Halm, et al.				
	AE 5,312,947	5/1994	Tsukuno, et al.				
	AF 6,368,359	4/2002	Perry, et al.				
	AG 5,276,173	1/1994	Marko, et al.				
	AH 5,098,865	3/1992	Machado, et al.				
	AI 6,331,494	12/18/2001	Olson, et al.				
	AJ 6,147,009	11/14/2000	Grill, et al.				
3/B	AK 6,484,082	11/26/2002	Cho, et al.				
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	DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLASSES	TRANSLATION YES NO	
						X (abstract only)	
3/B	AL 1321469A	6/25/2003	E.P.	X			
	AM 2004/027110A	4/1/2004	WO				
	AN 98/15499A	4/16/1998	WO				
3/B	AO 0543665	5/1993	E.P.				
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3/B				4/7/05			
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